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```
(image <sentence> (algin* or
register* or registrat*)) and
(parallel or ((uniform* or
constant* or consist*))
```

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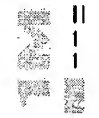
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(image <sentence> (algin* or register* or registrat*)) and ((line or bar* or grid or strip* or mark*) <paragraph>

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